

0101
Docket No. 247943US-2X



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Tatsuya KUNIKIYO, et al.

SERIAL NO: 10/760,449

GAU:

FILED: January 21, 2004

EXAMINER:

FOR: CAPACITANCE MEASUREMENT CIRCUIT

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☒ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.

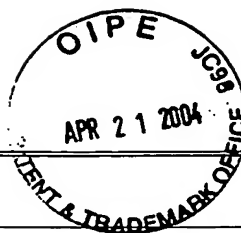
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Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
247943US-2XSERIAL NO.
10/760,449

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Tatsuya KUNIKIYO, et al.FILING DATE
January 21, 2004

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	6,300,765	10/09/01	CHEN			
	AB	5,999,010	12/07/99	ARORA ET AL.			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	Jai-Hoon SIM, et al., 1998 Symposium on VLSI Technology Digest of Technical Papers, Pages 32-33, "THE IMPACT OF ISOLATION PITCH SCALING ON V_{th} FLUCTUATION IN DRAM CELL TRANSISTORS DUE TO NEIGHBORING DRAIN/SOURCE ELECTRIC FIELD PENETRATION," June 9-11, 1998
	AX	James C. CHEN, et al., Technical Digest of IEDM, pages 69-72, "AN ON-CHIP, ATTOFARAD INTERCONNECT CHARGE-BASED CAPACITANCE MEASUREMENT (CBCM) TECHNIQUE," 1996
	AY	K. YAMADA, et al., 2003 Symposium on VLSI Technology Digest of Technical Papers, pages 111-112, "ACCURATE MODELING METHOD FOR DEEP SUB-MICRON Cu INTERCONNECT," June 10-12, 2003/Kyoto
	AZ	<div><input type="checkbox"/> Additional References sheet(s) attached</div>

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



LIST OF RELATED CASES

<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Inventor/ Applicant</u>
PER CLIENT	10/355,068	01/31/03	YAMASHITA et al.
227009US2X	10/232,689	09/03/02	KUNIKIYO et al.
229544US2	10/287,537	11/05/02	OKAGAKI et al.
247943US2X*	10/760,449	01/21/04	KUNIKIYO et al.

*Present Application; listed for information

GJM/sb

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